

High Resolution High Resonance frequency Semicontact / Noncontact AFM Cantilevers HA HR series, each chip has 2 cantilevers, resonant frequency 380 kHz / 230 kHz, force constant 34 N/m / 17 N/m

Art. ID	TIPS-HA_HR/400
Unit	400 separated chips
Deliverydetails	No Dangerous Good /not restricted

Description

High Resolution High Resonant Frequency AFM Cantilevers HA_HR series are designed for Semicontact (Intermittent), Noncontact applications. Each probe has 2 rectangular cantilevers. Typical Resonant Frequency 380kHz / 230kHz (dispersion $\pm 10\%$), Typical Force Constant 34N/m / 17N/m (dispersion $\pm 20\%$). Cantilever has Au reflective side coating to increase laser signal. Probes are also available with no coating as well as with conductive tip coating / Probes are packed in boxes with 15 and 50 pieces. Amount discount is included in the package price / High Accuracy composite ETALON probes combine the main features allowing to obtain high quality AFM images:
/// Sharp tip - curvature radius < 10 nm /// Resonance frequency, specified with high accuracy - $\pm 10\%$ within a wafer
/// Special chip geometry with vertical sidewalls for convenient operating /// High aspect ratio tip /// Enhanced back-side reflection of the cantilever /// Cost effective price